Search Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination	_
10/705,498	GEORGE ET AL.	
Examiner	Art Unit	
Scott I Jarrett	3623	

SEARCHED				
Class	Subclass	Date	Examiner	
700	100, 101	11/4/2004	SJ	
705	1, 8, 10	11/4/2004	SJ	
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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SEARCH NOT (INCLUDING SEARCH	_)
	DATE	EXMR
IEEE Keyword: George Michael, work in process/progress, batch/lot sizing, value stream mapping, lean manufacturing, design	11/4/2004	SJ
IEEE Keyworkd: design for manufacturing/manufacturability, design for production, cost modeling, little's law, supply chain	11/9/2004	SJ
EAST: dfp, dfm, cost modeling, little's law, supply chain, wip, lean manufacturing, george michael, motion of process, synch	11/4/2004	SJ
ACM dfp, dfm, cost modeling, little's law, supply chain, wip, lean manufacturing, george michael, motion of process, synch	11/8/2004	SJ
JSTOR dfp, dfm, cost modeling, little's law, supply chain, wip, lean manufacturing, george michael, motion of process, synch	11/4/2004	SJ
PALM Inventor and Assigment search	11/4/2004	. sı
Dialog dfp, dfm, cost modeling, little's law, supply chain, wip, lean manufacturing, george michael, motion of process, synch	11/9/2004	SJ